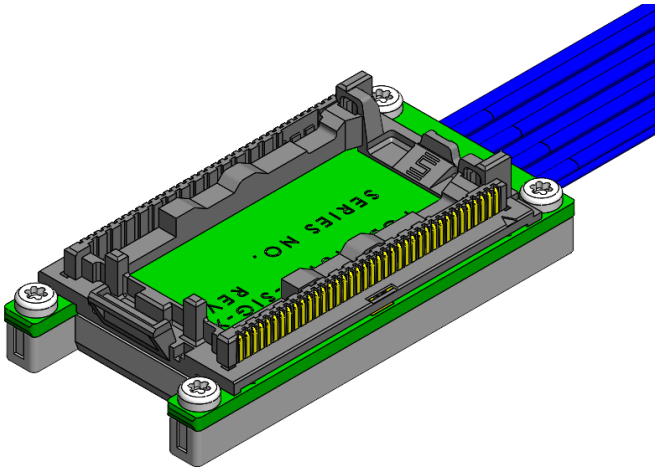
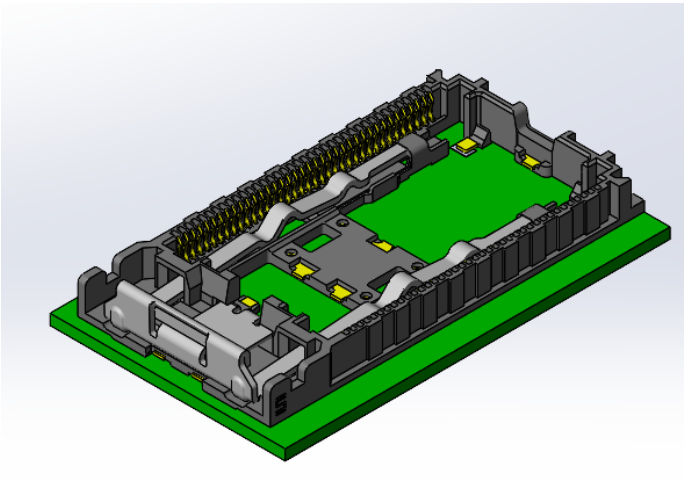
Project: Design Qualification Test Report	Tracking Code: CR-1108101_Report_Rev_1
Requested by:Leo Lee	Date: 10/28/2025
Part #: HALO-PE-01-4-XXXX/HLF6-38-03.5-S-2-2	
Part description: HALO / HLF6	Tech: Peter Chen
Test Start: 12/10/2024	Test Completed: 1/10/2025





DESIGN QUALIFICATION TEST REPORT

HALO / HLF6
HALO-PE-01-4-XXXX/HLF6-38-03.5-S-2-2

REVISION HISTORY

DATA	REV.NUM.	DESCRIPTION	ENG
7/21/2025	**1**	**Initial test**	**PC**

CERTIFICATION

All instruments and measuring equipment were calibrated to National Institute for Standards and Technology (NIST) traceable standards according to IS0 10012-l and ANSI/NCSL 2540-1, as applicable.

SCOPE

To perform the following tests: Design Qualification test. Please see test plan.

APPLICABLE DOCUMENTS

Standards: EIA Publication 364

TEST SAMPLES AND PREPARATION

1) All materials were manufactured in accordance with the applicable product specification.
2) All test samples were identified and encoded to maintain traceability throughout the test sequences.
3) After soldering, the parts to be used for LLCR and DWV/IR testing were cleaned according to CO-SC-WI-3029.
4) Either an automated cleaning procedure or an ultrasonic cleaning procedure may be used.
5) The automated procedure is used with aqueous compatible soldering materials.
6) Parts not intended for testing LLCR and DWV/IR are visually inspected and cleaned if necessary.
7) Any additional preparation will be noted in the individual test sequences.
8) Solder Information: Lead Free
9) Samtec Test PCBs used: PCB-113427-TST/PCB-113428-TST/PCB-113429-TST/PCB-114409-TST-XX.

FLOWCHARTS

Gas Tight

Group 1
HALO-PE-01-4-XXXX
HLF6-38-03.5-S-2-2
8 Assemblies

Step	Description
1.	LLCR (2)
2.	Gas Tight (1)
3.	LLCR (2) Max Delta = 15 mOhm

(1) Gas Tight = EIA-364-36

(2) LLCR = EIA-364-23
Open Circuit Voltage = 20 mV Max
Test Current = 100 mA Max

Normal Force

Group 1
HALO-PE-01-4-XXXX
HLF6-38-03.5-S-2-2
8 Contacts Minimum
Row 1 Without Thermals

Step	Description
1.	Contact Gaps
2.	Normal Force (1) Deflection = 0.0118 " Expected Force at Max Deflection = 71.4 g

Group 2
HALO-PE-01-4-XXXX
HLF6-38-03.5-S-2-2
8 Contacts Minimum
Row 2 Without Thermals

Step	Description
1.	Contact Gaps
2.	Normal Force (1) Deflection = 0.0118 " Expected Force at Max Deflection = 69.1 g

Group 3
HALO-PE-01-4-XXXX
HLF6-38-03.5-S-2-2
8 Contacts Minimum
Row 1 With Thermals

Step	Description
1.	Contact Gaps
2.	Thermal Age (2)
3.	Contact Gaps
4.	Normal Force (1) Deflection = 0.0118 " Expected Force at Max Deflection = 71.4 g

Group 4
HALO-PE-01-4-XXXX
HLF6-38-03.5-S-2-2
8 Contacts Minimum
Row 2 With Thermals

Step	Description
1.	Contact Gaps
2.	Thermal Age (2)
3.	Contact Gaps
4.	Normal Force (1) Deflection = 0.0118 " Expected Force at Max Deflection = 69.1 g

(1) Normal Force = EIA-364-04

(2) Thermal Age = EIA-364-17
Test Condition = 4 (105°C)
Time Condition = B (250 Hours)

FLOWCHARTS Continued

Thermal Aging

Group 1
HALO-PE-01-4-XXXX
HLF6-38-03.5-S-2-2
8 Assemblies

Step	Description
1.	Contact Gaps
2.	Mating/Unmating Force (2)
3.	LLCR (1)
4.	Thermal Age (3)
5.	LLCR (1) Max Delta = 15 mOhm
6.	Mating/Unmating Force (2)
7.	Contact Gaps

(1) LLCR = EIA-364-23
Open Circuit Voltage = 20 mV Max
Test Current = 100 mA Max

(2) Mating/Unmating Force = EIA-364-13

(3) Thermal Age = EIA-364-17
Test Condition = 4 (105°C)
Time Condition = B (250 Hours)

FLOWCHARTS Continued

Mating/Unmating/Durability

Group 1
HALO-PE-01-4-XXXX
HLF6-38-03.5-S-2-2
8 Assemblies

Step	Description
1.	Contact Gaps
2.	LLCR (2)
3.	Mating/Unmating Force (3)
4.	Cycles Quantity = 25 Cycles
5.	Mating/Unmating Force (3)
6.	Contact Gaps
7.	LLCR (2) Max Delta = 15 mOhm
8.	Thermal Shock (4)
9.	LLCR (2) Max Delta = 15 mOhm
10.	Humidity (1)
11.	LLCR (2) Max Delta = 15 mOhm
12.	Mating/Unmating Force (3)

(1) Humidity = EIA-364-31
Test Condition = B (240 Hours)
Test Method = III (+25°C to +65°C @ 90% RH to 98% RH)
Test Exceptions: ambient pre-condition and delete steps 7a and 7b

(2) LLCR = EIA-364-23
Open Circuit Voltage = 20 mV Max
Test Current = 100 mA Max

(3) Mating/Unmating Force = EIA-364-13

(4) Thermal Shock = EIA-364-32
Exposure Time at Temperature Extremes = 1/2 Hour
Method A, Test Condition = I (-55°C to +85°C)
Test Duration = A-3 (100 Cycles)

FLOWCHARTS Continued

IR/DWV

Pin-to-Pin

Group 1 HALO-PE-01-4-XXXX HLF6-38-03.5-S-2-2 2 Assemblies		Group 2 HALO-PE-01-4-XXXX 2 Assemblies		Group 3 HALO-PE-01-4-XXXX HLF6-38-03.5-S-2-2 2 Assemblies		Group 10 HLF6-38-03.5-S-2-2 2 Assemblies	
Step	**Description**	**Step**	**Description**	**Step**	**Description**	**Step**	**Description**
1.	DWV Breakdown (2)	1.	DWV Breakdown (2)	1.	IR (4)	1.	DWV Breakdown (2)
				2.	DWV at Test Voltage (1)		
				3.	Thermal Shock (5)		
				4.	IR (4)		
				5.	DWV at Test Voltage (1)		
				6.	Humidity (3)		
				7.	IR (4)		
				8.	DWV at Test Voltage (1)		

Row-to-Row

Group 4 HALO-PE-01-4-XXXX HLF6-38-03.5-S-2-2 2 Assemblies		Group 5 HALO-PE-01-4-XXXX 2 Assemblies		Group 6 HALO-PE-01-4-XXXX HLF6-38-03.5-S-2-2 2 Assemblies		Group 11 HLF6-38-03.5-S-2-2 2 Assemblies	
Step	**Description**	**Step**	**Description**	**Step**	**Description**	**Step**	**Description**
1.	DWV Breakdown (2)	1.	DWV Breakdown (2)	1.	IR (4)	1.	DWV Breakdown (2)
				2.	DWV at Test Voltage (1)		
				3.	Thermal Shock (5)		
				4.	IR (4)		
				5.	DWV at Test Voltage (1)		
				6.	Humidity (3)		
				7.	IR (4)		
				8.	DWV at Test Voltage (1)		

FLOWCHARTS Continued

Pin-to-Ground

Group 7 HALO-PE-01-4-XXXX HLF6-38-03.5-S-2-2 2 Assemblies		Group 8 HALO-PE-01-4-XXXX 2 Assemblies		Group 9 HALO-PE-01-4-XXXX HLF6-38-03.5-S-2-2 2 Assemblies		Group 12 HLF6-38-03.5-S-2-2 2 Assemblies	
Step	**Description**	**Step**	**Description**	**Step**	**Description**	**Step**	**Description**
1.	DWV Breakdown (2)	1.	DWV Breakdown (2)	1.	IR (4)	1.	DWV Breakdown (2)
				2.	DWV at Test Voltage (1)		
				3.	Thermal Shock (5)		
				4.	IR (4)		
				5.	DWV at Test Voltage (1)		
				6.	Humidity (3)		
				7.	IR (4)		
				8.	DWV at Test Voltage (1)		

(1) DWV at Test Voltage = EIA-364-20
Test Condition = 1 (Sea Level)
DWV test voltage is equal to 75% of the lowest breakdown voltage
Test voltage applied for 60 seconds

(2) DWV Breakdown = EIA-364-20
Test Condition = 1 (Sea Level)
DWV test voltage is equal to 75% of the lowest breakdown voltage
Test voltage applied for 60 seconds

(3) Humidity = EIA-364-31
Test Condition = B (240 Hours)
Test Method = III (+25°C to +65°C @ 90% RH to 98% RH)
Test Exceptions: ambient pre-condition and delete steps 7a and 7b

(4) IR = EIA-364-21
Test Condition = 500 Vdc, 2 Minutes Max

(5) Thermal Shock = EIA-364-32
Exposure Time at Temperature Extremes = 1/2 Hour
Method A, Test Condition = I (-55°C to +85°C)
Test Duration = A-3 (100 Cycles)

FLOWCHARTS Continued

Current Carrying Capacity

Group 1	Group 2	Group 3	Group 4
HALO-PE-01-4-XXXX	HALO-PE-01-4-XXXX	HALO-PE-01-4-XXXX	HALO-PE-01-4-XXXX
HLF6-38-03.5-S-2-2	HLF6-38-03.5-S-2-2	HLF6-38-03.5-S-2-2	HLF6-38-03.5-S-2-2
4 Pins Powered	8 Pins Powered	16 Pins Powered	32 Pins Powered
Signal	Signal	Signal	Signal
Note: No Connection (Row A/B position 1,4,7,10,13~26,29,32,35 & 38)	*Note: No Connection (Row A/B position 1,4,7,10,13~26,29,32,35 & 38)*	*Note: No Connection (Row A/B position 1,4,7,10,13~26,29,32,35 & 38)*	*Note: All pins powered except: Row A position 1,4,7,10,13~26,29,32,35 & 38; Row B position 1,4,7,10,13~26,29,32,35 & 38*
Step **Description**	**Step** **Description**	**Step** **Description**	**Step** **Description**
1. CCC (1) Number of Positions = 4 Rows = 1	1. CCC (1) Rows = 2 Number of Positions = 4	1. CCC (1) Rows = 2 Number of Positions = 8	1. CCC (1) Rows = 2 Number of Positions = 16

(1) CCC = EIA-364-70
Method 2, Temperature Rise Versus Current Curve
(TIN PLATING) - Tabulate calculated current at RT, 65°C, 75°C and 95°C after derating 20% and based on 105°C
(GOLD PLATING) - Tabulate calculated current at RT, 85°C, 95°C and 115°C after derating 20% and based on 125°C

Mechanical Shock/Random Vibration/LLCR

Group 1
HALO-PE-01-4-XXXX
HLF6-38-03.5-S-2-2
4 Assemblies

Step	Description
1.	LLCR (1)
2.	Mechanical Shock (2) - Non Standard
3.	Random Vibration (3)
4.	LLCR (1) Max Delta = 15 mOhm

(1) LLCR = EIA-364-23
Open Circuit Voltage = 20 mV Max
Test Current = 100 mA Max

(2) Mechanical Shock = Other
Test Condition = A (50 G Peak, 11 milliseconds, Half Sine)
Number of Shocks = 3 Per Direction, Per Axis, 18 Total

(3) Random Vibration = EIA-364-28
Condition = VB (7.56 gRMS Average, 2 Hours/Axis)

FLOWCHARTS Continued

Mechanical Shock/Random Vibration/Event Detection

Group 1
HALO-PE-01-4-XXXX
HLF6-38-03.5-S-2-2
60 Points

Step	Description
1.	Nanosecond Event Detection (Mechanical Shock) (1) - Non Standard
2.	Nanosecond Event Detection (Random Vibration) (2)

(1) Nanosecond Event Detection (Mechanical Shock) = Other
Use EIA-364-87 for Nanosecond Event Detection:
Test Condition = F (50 nanoseconds at 10 ohms)
Use EIA-364-27 for Mechanical Shock:
Test Condition = A (50 G Peak, 11 milliseconds, Half Sine)
Number of Shocks = 3 Per Direction, Per Axis, 18 Total

(2) Nanosecond Event Detection (Random Vibration)
Use EIA-364-87 for Nanosecond Event Detection:
Test Condition = F (50 nanoseconds at 10 ohms)
Use EIA-364-28 for Random Vibration:
Condition = VB (7.56 gRMS Average, 2 Hours/Axis)

Cable Pull

Group 1
HALO-PE-01-4-XXXX
HLF6-38-03.5-S-2-2
2 Assemblies
0 Degrees

Step	Description
1.	Cable Pull (1)

Group 2
HALO-PE-01-4-XXXX
HLF6-38-03.5-S-2-2
2 Assemblies
90 Degrees

Step	Description
1.	Cable Pull (1)

(1) Cable Pull = EIA-364-38
Measure and Record Force Required to Failure
Failure = Discontinuity >1 microsecond at 10 ohms

FLOWCHARTS Continued

Cable Flex

Group 1

HALO-PE-01-4-XXXX

HLF6-38-03.5-S-2-2

2 Assemblies

Circular Cable

Step	Description
1.	IR (3)
2.	DWV at Test Voltage (2)
3.	Cable Flex (1) *Note: 1.Set weight beginning from 8oz and decrease progressively (8oz -> 4oz -> 2oz) until the cable assembly can be withstanded. 2.Mandrel size: Radius 0.625 inches.*
4.	Visual Inspection
5.	IR (3)
6.	DWV at Test Voltage (2)

Group 2

HALO-PE-01-4-XXXX

HLF6-38-03.5-S-2-2

2 Assemblies

Circular Cable

Note: Rotate 90 degree.

Step	Description
1.	IR (3)
2.	DWV at Test Voltage (2)
3.	Cable Flex (1) *Note: 1.Set weight beginning from 8oz and decrease progressively (8oz -> 4oz -> 2oz) until the cable assembly can be withstanded. 2.Mandrel size: Radius 0.625 inches.*
4.	Visual Inspection
5.	IR (3)
6.	DWV at Test Voltage (2)

(1) Cable Flex = EIA-364-41
Circular Jacket Cable - to be tested 90° each direction (180° total)
Flat Cable - to be tested 70° each direction (140° total)
Monitor continuity during flex testing
Failure = Discontinuity >1 microsecond at 10 ohms

(2) DWV at Test Voltage = EIA-364-20
Test Condition = 1 (Sea Level)
DWV test voltage is equal to 75% of the lowest breakdown voltage
Test voltage applied for 60 seconds

(3) IR = EIA-364-21
Test Condition = 500 Vdc, 2 Minutes Max

ATTRIBUTE DEFINITIONS

The following is a brief, simplified description of attributes.

THERMAL:

1) EIA-364-17, *Temperature Life with or without Electrical Load Test Procedure for Electrical Connectors.*
2) Test Condition at 105° C.
3) Test Time Condition B for 250 hours.
4) All test samples are pre-conditioned at ambient.
5) All test samples are exposed to environmental stressing in the mated condition.

THERMAL SHOCK:

1) EIA-364-32, *Thermal Shock (Temperature Cycling) Test Procedure for Electrical Connectors.*
2) Test Condition I: -55°C to +85°C
3) Test Time: ½ hour dwell at each temperature extreme
4) Number of Cycles: 100
5) All test samples are pre-conditioned at ambient.
6) All test samples are exposed to environmental stressing in the mated condition.

HUMIDITY:

1) Reference document: EIA-364-31, *Humidity Test Procedure for Electrical Connectors.*
2) Test Condition B, 240 Hours.
3) Method III, +25° C to + 65° C, 90% to 98% Relative Humidity excluding sub-cycles 7a and 7b.
4) All samples are pre-conditioned at ambient.
5) All test samples are exposed to environmental stressing in the mated condition.

MECHANICAL SHOCK (Specified Pulse):

1) Reference document: EIA-364-27, *Mechanical Shock Test Procedure for Electrical Connectors*
2) Test Condition A
3) Peak Value: 50 G
4) Duration: 11 Milliseconds
5) Wave Form: Half Sine
6) Number of Shocks: 3 Shocks / Direction, 3 Axis (18 Total)

VIBRATION:

1) Reference document: EIA-364-28, *Vibration Test Procedure for Electrical Connectors*
2) Test Condition V, Letter B
3) Power Spectral Density: 0.10 G^2 / Hz
4) G 'RMS': 7.56
5) Frequency: 50 to 2000 Hz
6) Duration: 2.0 Hours per axis (3 axis total)

NANOSECOND-EVENT DETECTION:

1) Reference document: EIA-364-87, *Nanosecond-Event Detection for Electrical Connectors*
2) Prior to test, the samples were characterized to assure the low nanosecond event being monitored will trigger the detector.
3) After characterization it was determined the test samples could be monitored for 50 nanosecond events

MATING/UNMATING:

1) Reference document: EIA-364-13, *Mating and Unmating Forces Test Procedure for Electrical Connectors.*
2) The full insertion position was to within 0.003" to 0.004" of the plug bottoming out in the receptacle to prevent damage to the system under test.
3) One of the mating parts is secured to a floating X-Y table to prevent damage during cycling.

ATTRIBUTE DEFINITIONS Continued

The following is a brief, simplified description of attributes

TEMPERATURE RISE (Current Carrying Capacity, CCC):

1) EIA-364-70, *Temperature Rise versus Current Test Procedure for Electrical Connectors and Sockets*.
2) When current passes through a contact, the temperature of the contact increases as a result of I^2R (resistive) heating.
3) The number of contacts being investigated plays a significant part in power dissipation and therefore temperature rise.
4) The size of the temperature probe can affect the measured temperature.
5) Copper traces on PC boards will contribute to temperature rise:
    a. Self-heating (resistive)
    b. Reduction in heat sink capacity affecting the heated contacts
6) A de-rating curve, usually 20%, is calculated.
7) Calculated de-rated currents at four temperature points are reported:
    a. Ambient
    b. 85^{o} C
    c. 95^{o} C
    d. 115^{o} C
8) Typically, neighboring contacts (in close proximity to maximize heat buildup) are energized.
9) The thermocouple (or temperature measuring probe) will be positioned at a location to sense the maximum temperature in the vicinity of the heat generation area.
10) A computer program, *TR 803.exe*, ensures accurate stability for data acquisition.
11) Hook-up wire cross section is larger than the cross section of any connector leads/PC board traces, jumpers, etc.
12) Hook-up wire length is longer than the minimum specified in the referencing standard.

NORMAL FORCE (FOR CONTACTS TESTED OUTSIDE THE HOUSING):

1) Reference document: EIA-364-04, *Normal Force Test Procedure for Electrical Connectors*.
2) The contacts shall be tested in the loose state, *not* inserted in connector housing.
3) The contacts shall be prepared to allow access to the spring member at the same attitude and deflection level as would occur in actual use.
4) In the event that portions of the contact prevent insertion of the test probe and/or deflection of the spring member under evaluation, said material shall be removed leaving the appropriate contact surfaces exposed.
5) In the case of multi-tine contacts, each tine shall be tested independently on separate samples as required.
6) The connector housing shall be simulated, if required, in order to provide an accurate representation of the actual contact system performance.
7) A holding fixture shall be fashioned to allow the contact to be properly deflected.
8) Said holding fixture shall be mounted on a floating, adjustable, X-Y table on the base of the Dillon TC^2, computer controlled test stand with a deflection measurement system accuracy of 5 μm (0.0002”).
9) The probe shall be attached to a Dillon P/N 49761-0105, 5 N (1.1 Lb) load cell providing an accuracy of ± 0.2%.
10) The nominal deflection rate shall be 5 mm (0.2”)/minute.
11) Unless otherwise noted a minimum of five contacts shall be tested.
12) The force/deflection characteristic to load and unload each contact shall be repeated five times.
13) The system shall utilize the TC^2 software in order to acquire and record the test data.
14) The permanent set of each contact shall be measured within the TC^2 software.
15) The acquired data shall be graphed with the deflection data on the X-axis and the force data on the Y-axis and a print out will be stored with the Tracking Code paperwork.

ATTRIBUTE DEFINITIONS Continued

The following is a brief, simplified description of attributes

LLCR:

1) EIA-364-23, *Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets*.
2) A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
3) The following guidelines are used to categorize the changes in LLCR as a result from stressing
    a. <= +5.0 mOhms: ---------- Stable
    b. +5.1 to +10.0 mOhms:---------- Minor
    c. +10.1 to +15.0 mOhms: ---------- Acceptable
    d. +15.1 to +50.0 mOhms: ---------- Marginal
    e. +50.1 to +1000 mOhms: ---------- Unstable
    f. >+1000 mOhms:---------- Open Failure

GAS TIGHT:

To provide method for evaluating the ability of the contacting surfaces in preventing penetration of harsh vapors which might lead to oxide formation that may degrade the electrical performance of the contact system.

1) EIA-364-23, *Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets*.
2) A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
3) The following guidelines are used to categorize the changes in LLCR as a result from stressing
    a. <= +5.0 mOhms:---------- Stable
    b. +5.1 to +10.0 mOhms: ---------- Minor
    c. +10.1 to +15.0 mOhms: ---------- Acceptable
    d. +15.1 to +50.0 mOhms: ---------- Marginal
    e. +50.1 to +1000 mOhms:---------- Unstable
    f. >+1000 mOhms:---------- Open Failure

4) Procedure:
    a. Reference document: EIA-364-36, *Test Procedure for Determination of Gas-Tight Characteristics for Electrical Connectors, Sockets and/or Contact Systems*.
    b. Test Conditions:
        i. Class II--- Mated pairs of contacts assembled to their plastic housings.
        ii. Reagent grade Nitric Acid shall be used of sufficient volume to saturate the test chamber
        iii. The ratio of the volume of the test chamber to the surface area of the acid shall be 10:1.
        iv. The chamber shall be saturated with the vapor for at least 15 minutes before samples are added.
        v. Exposure time, 55 to 65 minutes.
        vi. The samples shall be no closer to the chamber walls than 1 inches and no closer to the surface of the acid than 3 inches.
        vii. The samples shall be dried after exposure for a minimum of 1 hour.
        viii. Drying temperature 50^{o} C
        ix. The final LLCR shall be conducted within 1 hour after drying.

ATTRIBUTE DEFINITIONS Continued

The following is a brief, simplified description of attributes

INSULATION RESISTANCE (IR):

To determine the resistance of insulation materials to leakage of current through or on the surface of these materials when a DC potential is applied.

1) PROCEDURE:
    a. Reference document: EIA-364-21, *Insulation Resistance Test Procedure for Electrical Connectors*.
    b. Test Conditions:
        i. Between Adjacent Contacts or Signal-to-Ground
        ii. Electrification Time 2.0 minutes
        iii. Test Voltage (500 VDC) corresponds to calibration settings for measuring resistances.
2) MEASUREMENTS:
3) When the specified test voltage is applied (VDC), the insulation resistance shall not be less than 1000 megohms.

DIELECTRIC WITHSTANDING VOLTAGE (DWV):

To determine if the sockets can operate at its rated voltage and withstand momentary over potentials due to switching, surges, and other similar phenomenon. Separate samples are used to evaluate the effect of environmental stresses so not to influence the readings from arcing that occurs during the measurement process.

1) PROCEDURE:
    a. Reference document: EIA-364-20, *Withstanding Voltage Test Procedure for Electrical Connectors*.
    b. Test Conditions:
        i. Between Adjacent Contacts or Signal-to-Ground
        ii. Barometric Test Condition 1
        iii. Rate of Application 500 V/Sec
        iv. Test Voltage (VAC) until breakdown occurs
2) MEASUREMENTS/CALCULATIONS
    a. The breakdown voltage shall be measured and recorded.
    b. The dielectric withstanding voltage shall be recorded as 75% of the minimum breakdown voltage.
    c. The working voltage shall be recorded as one-third (1/3) of the dielectric withstanding voltage (one-fourth of the breakdown voltage).

ATTRIBUTE DEFINITIONS Continued

The following is a brief, simplified description of attributes

CABLE PULL:

1) Secure cable near center and pull on connector
    a. At 0°, in-line with cable
    b. At 90°, in-line with cable

Fig. 1
0° Connector pull

CABLE Flex:

1) Oscillate and monitor electrical continuity for open circuit indication.
    a. ± 90°Flex Mode, bend up to 200 cycles. load on 8 oz.

Fig. 2
(Setup picture)

RESULTS

Temperature Rise, CCC at a 20% de-rating

- **CCC for a 30°C Temperature Rise----------0.93 A per contact with 4 contact (2 x 2) powered**
- **CCC for a 30°C Temperature Rise----------0.82 A per contact with 8 contacts (2 x 4) powered**
- **CCC for a 30°C Temperature Rise----------0.53 A per contact with 16 contacts (2 x 8) powered**
- **CCC for a 30°C Temperature Rise----------0.42 A per contact with 32 contacts (2 x 16) powered**
-

Mating – Unmating Forces

Thermal Aging Group

- **Initial**
  - **Mating**
    - **Min ---------- 1.91 lbs**
    - **Max---------- 2.71 lbs**
  - **Unmating**
    - **Min ---------- 0.43 lbs**
    - **Max---------- 0.61 lbs**
- **After Thermal**
  - **Mating**
    - **Min ---------- 1.00 lbs**
    - **Max---------- 1.13 lbs**
  - **Unmating**
    - **Min ---------- 0.42 lbs**
    - **Max---------- 0.94 lbs**

Mating/Unmating Durability Group

- **Initial**
  - **Mating**
    - **Min ---------- 1.27 lbs**
    - **Max---------- 1.68 lbs**
  - **Unmating**
    - **Min ---------- 0.45 lbs**
    - **Max---------- 0.75 lbs**
- **After 25 Cycles**
  - **Mating**
    - **Min ---------- 1.50 lbs**
    - **Max---------- 1.79 lbs**
  - **Unmating**
    - **Min ---------- 0.59 lbs**
    - **Max---------- 0.92 lbs**
- **After Humidity**
  - **Mating**
    - **Min ---------- 1.22 lbs**
    - **Max---------- 1.66 lbs**
  - **Unmating**
    - **Min ---------- 0.42 lbs**
    - **Max---------- 0.76 lbs**

RESULTS Continued

Cable Pull force

- **0° Pull**
  - **Min----------25.15 lbs**
  - **Max ----------30.05 lbs**
- **90° Pull**
  - **Min---------- 3.27 lbs**
  - **Max ---------- 4.54 lbs**

Normal Force at 0.0118 inches deflection

Row 1

- **Initial**
  - **Min----------51.40 gf Set ----- 0.0012 inch**
  - **Max ----------67.00 gf Set ----- 0.0020 inch**
- **Thermal**
  - **Min----------55.40 gf Set------ 0.0035 inch**
  - **Max ----------60.70 gf Set------ 0.0041 inch**

Row 2

- **Initial**
  - **Min----------55.70 gf Set ----- 0.0008 inch**
  - **Max ----------70.10 gf Set ----- 0.0016 inch**
- **Thermal**
  - **Min----------52.30 gf Set------ 0.0036 inch**
  - **Max ----------60.60 gf Set------ 0.0042 inch**

RESULTS Continued

Insulation Resistance minimums, IR

Pin to Pin

- **Initial**
  - **Mated ---------- 45000 Meg Ω ---------- Passed**
  - **Unmated ---------- 45000 Meg Ω ---------- Passed**
- **Thermal Shock**
  - **Mated ---------- 45000 Meg Ω ---------- Passed**
  - **Unmated ---------- 45000 Meg Ω ---------- Passed**
- **Humidity**
  - **Mated ---------- 45000 Meg Ω ---------- Passed**
  - **Unmated ---------- 45000 Meg Ω ---------- Passed**

Row to Row

- **Initial**
  - **Mated ---------- 45000 Meg Ω ---------- Passed**
  - **Unmated ---------- 45000 Meg Ω ---------- Passed**
- **Thermal Shock**
  - **Mated ---------- 45000 Meg Ω ---------- Passed**
  - **Unmated ---------- 45000 Meg Ω ---------- Passed**
- **Humidity**
  - **Mated ---------- 45000 Meg Ω ---------- Passed**
  - **Unmated ---------- 45000 Meg Ω ---------- Passed**

Pin to Ground

- **Initial**
  - **Mated ---------- 45000 Meg Ω ---------- Passed**
  - **Unmated ---------- 45000 Meg Ω ---------- Passed**
- **Thermal Shock**
  - **Mated ---------- 45000 Meg Ω ---------- Passed**
  - **Unmated ---------- 45000 Meg Ω ---------- Passed**
- **Humidity**
  - **Mated ---------- 3514 Meg Ω ---------- Passed**
  - **Unmated ---------- 4500 Meg Ω ---------- Passed**

Dielectric Withstanding Voltage minimums, DWV

- **Minimums**
  - **Breakdown Voltage ---------- 800 VAC**
  - **Test Voltage ---------- 600 VAC**
  - **Working Voltage ---------- 200 VAC**

Pin to Pin

- **Initial DWV ---------- Passed**
- **Thermal DWV ---------- Passed**
- **Humidity DWV ---------- Passed**

Row to Row

- **Initial DWV ---------- Passed**
- **Thermal DWV ---------- Passed**
- **Humidity DWV ---------- Passed**

Pin to Ground

- **Initial DWV ---------- Passed**
- **Thermal DWV ---------- Passed**
- **Humidity DWV ---------- Passed**

RESULTS Continued

Cable Flex:

Insulation Resistance minimums, IR

Pin to Pin

- **Initial**
  - **Mated----------45000 Meg Ω ---------- Passed**
- **After 200 flex cycles**
  - **Mated----------45000 Meg Ω ---------- Passed**

Row to Row

- **Initial**
  - **Mated----------45000 Meg Ω ---------- Passed**
- **After 200 flex cycles**
  - **Mated----------45000 Meg Ω ---------- Passed**

Pin to Ground

- **Initial**
  - **Mated----------45000 Meg Ω ---------- Passed**
- **After 200 flex cycles**
  - **Mated----------45000 Meg Ω ---------- Passed**

Dielectric Withstanding Voltage minimums, DWV

- **Test Voltage ----------450 VAC**

Pin to Pin

- **Initial DWV ----------Passed**
- **After 200 Flex cycles DWV ----------Passed**

Row to Row

- **Initial DWV ----------Passed**
- **After 200 Flex cycles DWV ----------Passed**

Pin to Ground

- **Initial DWV ----------Passed**
- **After 200 Flex cycles DWV ----------Passed**

RESULTS Continued

LLCR Gas Tight (192 LLCR test points)

- **Initial ---------- 424.38 mOhms Max**
- **Gas-Tight**
  - **<= +5.0 mOhms ---------- 152 Points ---------- Stable**
  - **+5.1 to +10.0 mOhms ---------- 27 Points ---------- Minor**
  - **+10.1 to +15.0 mOhms ---------- 13 Points ---------- Acceptable**
  - **+15.1 to +50.0 mOhms ---------- 0 Points ---------- Marginal**
  - **+50.1 to +1000 mOhms ---------- 0 Points ---------- Unstable**
  - **>+1000 mOhms ---------- 0 Points ---------- Open Failure**

LLCR Thermal Aging (192 LLCR test points)

- **Initial ---------- 424.39 mOhms Max**
- **Thermal Aging**
  - **<= +5.0 mOhms ---------- 93 Points ---------- Stable**
  - **+5.1 to +10.0 mOhms ---------- 57 Points ---------- Minor**
  - **+10.1 to +15.0 mOhms ---------- 42 Points ---------- Acceptable**
  - **+15.1 to +50.0 mOhms ---------- 0 Points ---------- Marginal**
  - **+50.1 to +1000 mOhms ---------- 0 Points ---------- Unstable**
  - **>+1000 mOhms ---------- 0 Points ---------- Open Failure**

LLCR Durability (192 LLCR test points)

- **Initial ---------- 423.16 mOhms Max**
- **Durability, 25 Cycles**
  - **<= +5.0 mOhms ---------- 107 Points ---------- Stable**
  - **+5.1 to +10.0 mOhms ---------- 47 Points ---------- Minor**
  - **+10.1 to +15.0 mOhms ---------- 38 Points ---------- Acceptable**
  - **+15.1 to +50.0 mOhms ---------- 0 Points ---------- Marginal**
  - **+50.1 to +1000 mOhms ---------- 0 Points ---------- Unstable**
  - **>+1000 mOhms ---------- 0 Points ---------- Open Failure**
- **Thermal**
  - **<= +5.0 mOhms ---------- 111 Points ---------- Stable**
  - **+5.1 to +10.0 mOhms ---------- 43 Points ---------- Minor**
  - **+10.1 to +15.0 mOhms ---------- 38 Points ---------- Acceptable**
  - **+15.1 to +50.0 mOhms ---------- 0 Points ---------- Marginal**
  - **+50.1 to +1000 mOhms ---------- 0 Points ---------- Unstable**
  - **>+1000 mOhms ---------- 0 Points ---------- Open Failure**
- **Humidity**
  - **<= +5.0 mOhms ---------- 97 Points ---------- Stable**
  - **+5.1 to +10.0 mOhms ---------- 66 Points ---------- Minor**
  - **+10.1 to +15.0 mOhms ---------- 29 Points ---------- Acceptable**
  - **+15.1 to +50.0 mOhms ---------- 0 Points ---------- Marginal**
  - **+50.1 to +1000 mOhms ---------- 0 Points ---------- Unstable**
  - **>+1000 mOhms ---------- 0 Points ---------- Open Failure**

RESULTS Continued

LLCR Shock & Vibration (256 LLCR test points)

- **Initial ---------- 430.9 mOhms Max**
- **Shock &Vibration**
  - **<= +5.0 mOhms ---------- 213 Points ---------- Stable**
  - **+5.1 to +10.0 mOhms ---------- 35 Points ---------- Minor**
  - **+10.1 to +15.0 mOhms ---------- 8 Points ---------- Acceptable**
  - **+15.1 to +50.0 mOhms ---------- 0 Points ---------- Marginal**
  - **+50.1 to +1000 mOhms ---------- 0 Points ---------- Unstable**
  - **>+1000 mOhms ---------- 0 Points ---------- Open Failure**

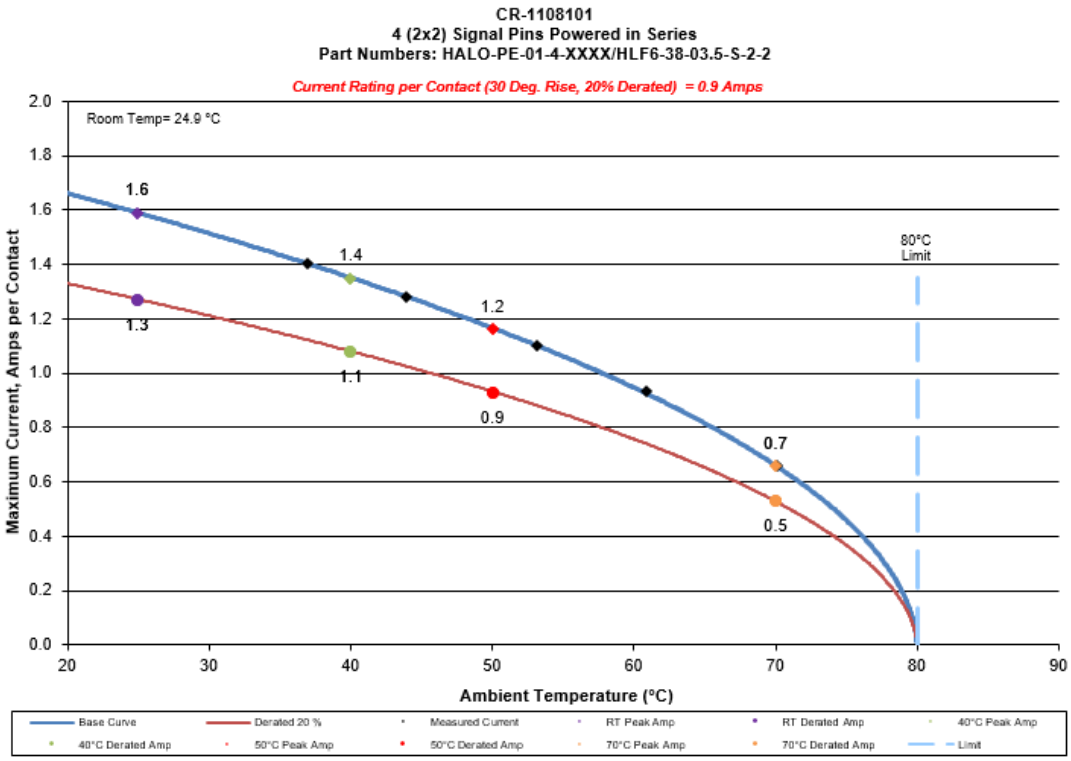
Mechanical Shock & Random Vibration:

- **Shock**
  - **No Damage ---------- ---------- Pass**
  - **50 Nanoseconds ---------- ---------- Pass**
- **Vibration**
  - **No Damage ---------- ---------- Pass**
  - **50 Nanoseconds ---------- ---------- Pass**

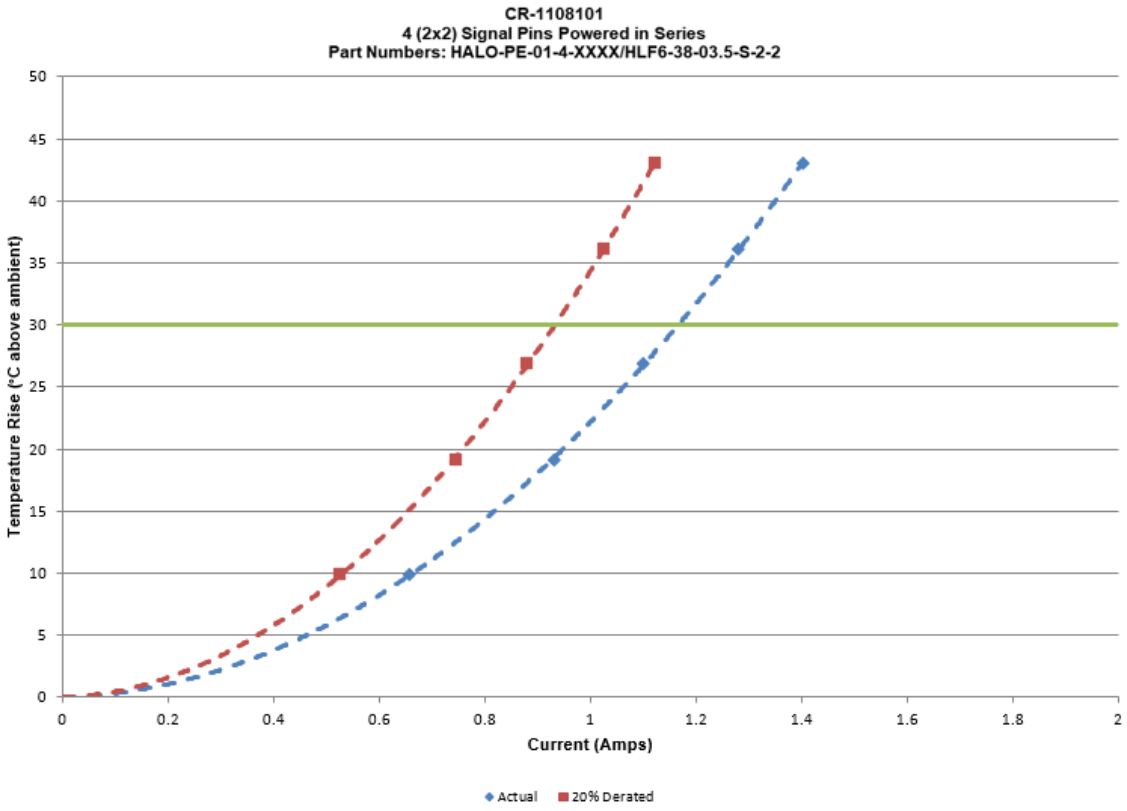
DATA SUMMARIES

TEMPERATURE RISE (Current Carrying Capacity, CCC):

1) High quality thermocouples whose temperature slopes track one another were used for temperature monitoring.
2) The thermocouples were placed at a location to sense the maximum temperature generated during testing.
3) Temperature readings recorded are those for which three successive readings, 15 minutes apart, differ less than 1° C (computer controlled data acquisition).
4) Adjacent contacts were powered:
    a. Linear configuration with 4 adjacent conductors/contacts powered

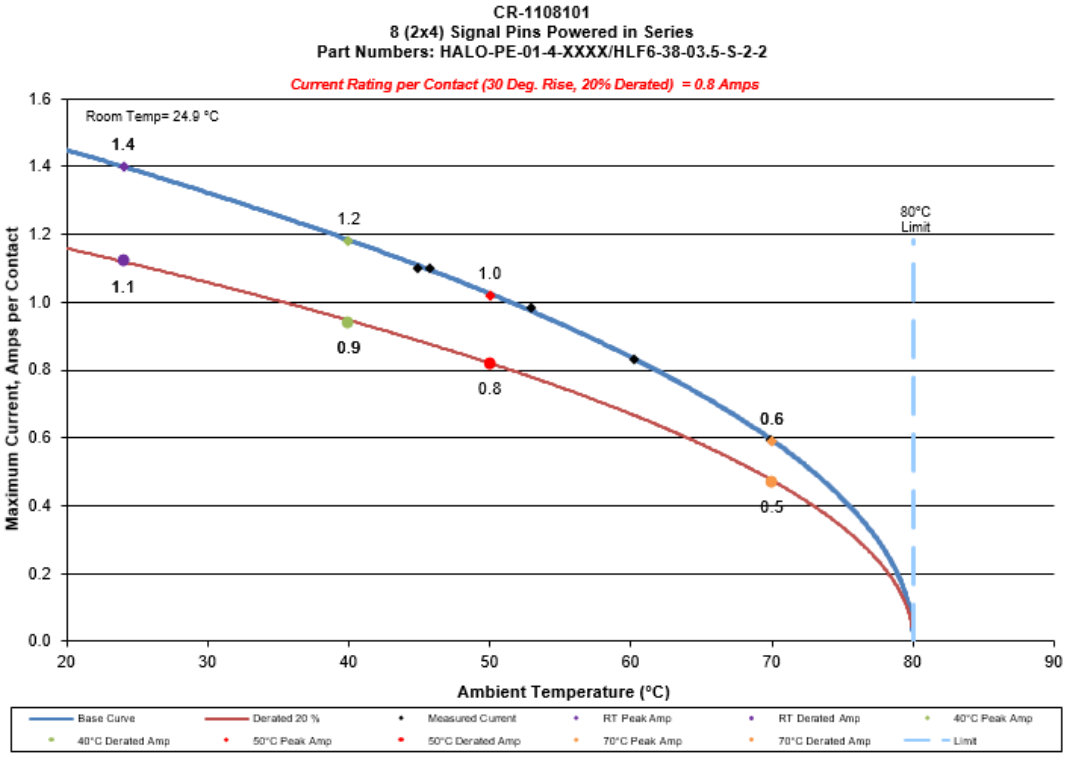


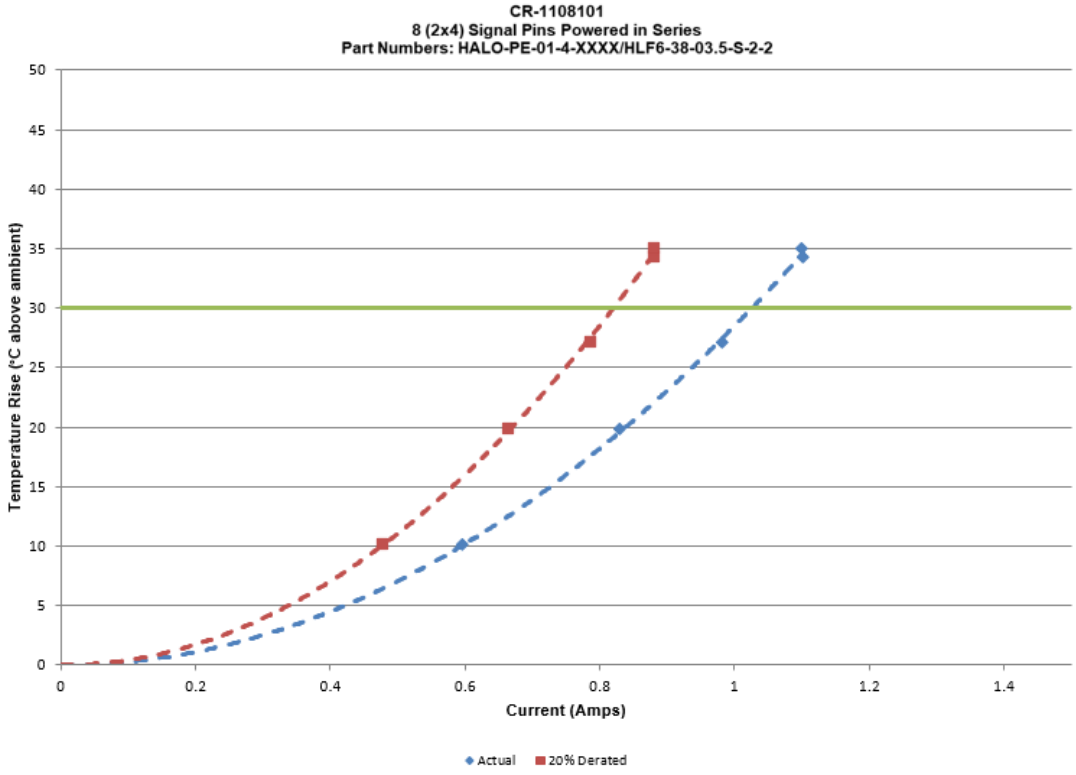
DATA SUMMARIES Continued



DATA SUMMARIES Continued

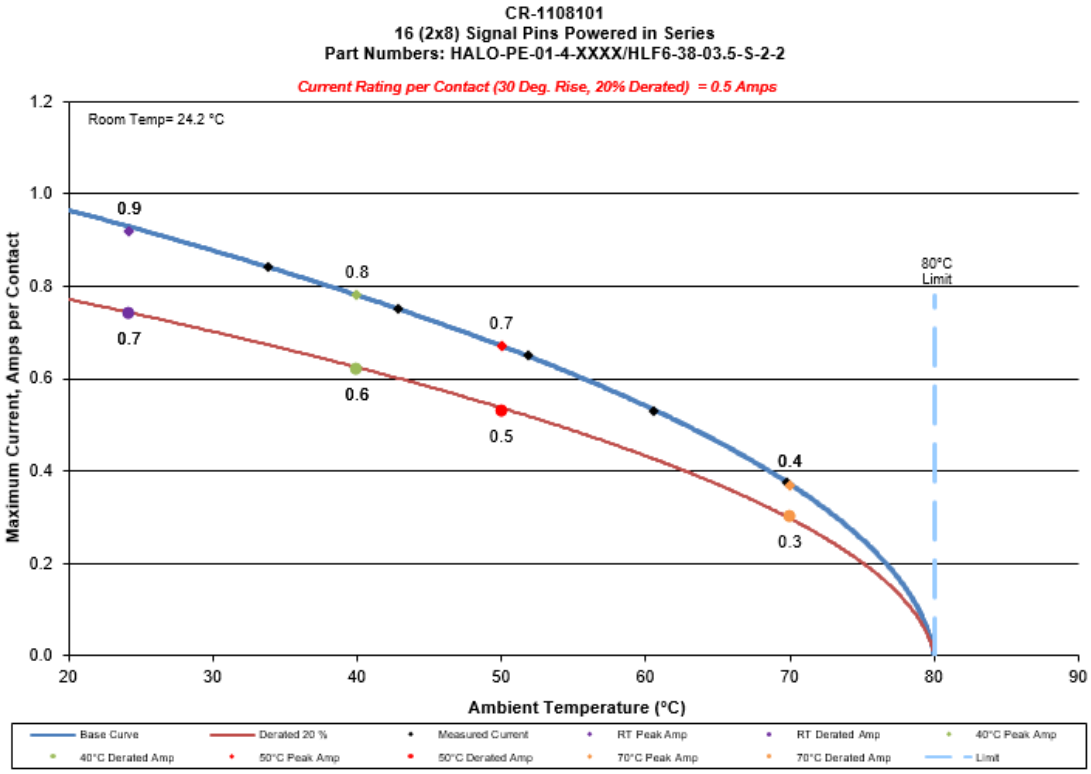
b. Linear configuration with 8 adjacent conductors/contacts powered

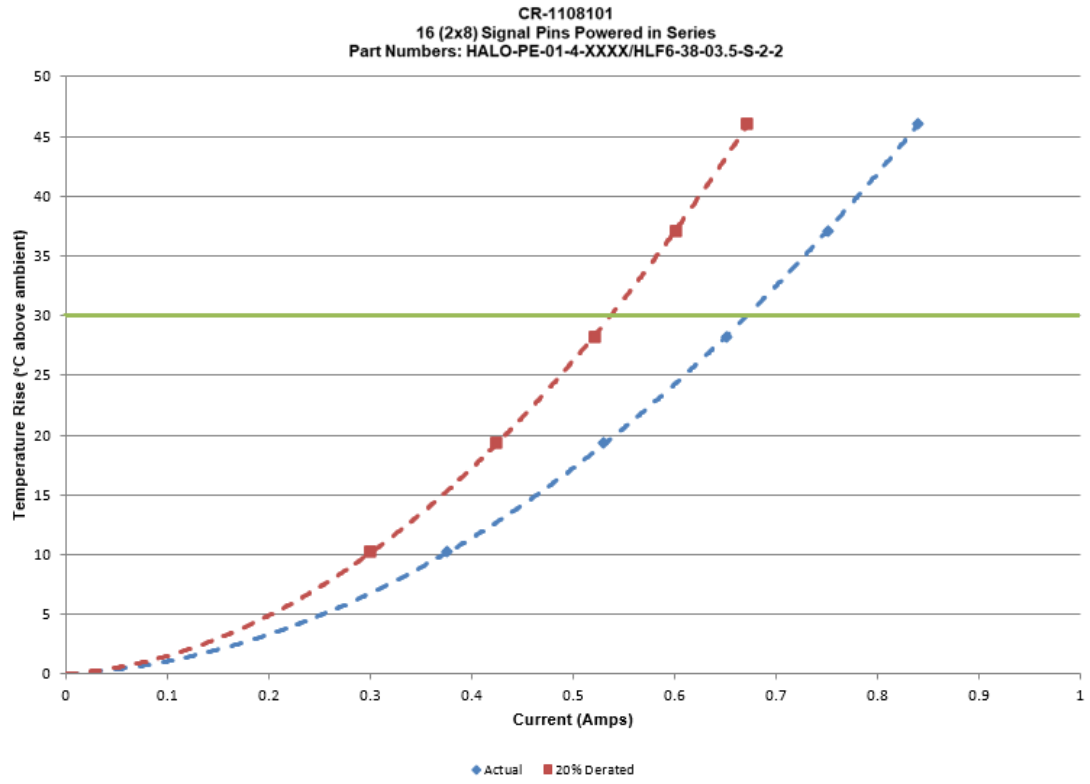




DATA SUMMARIES Continued

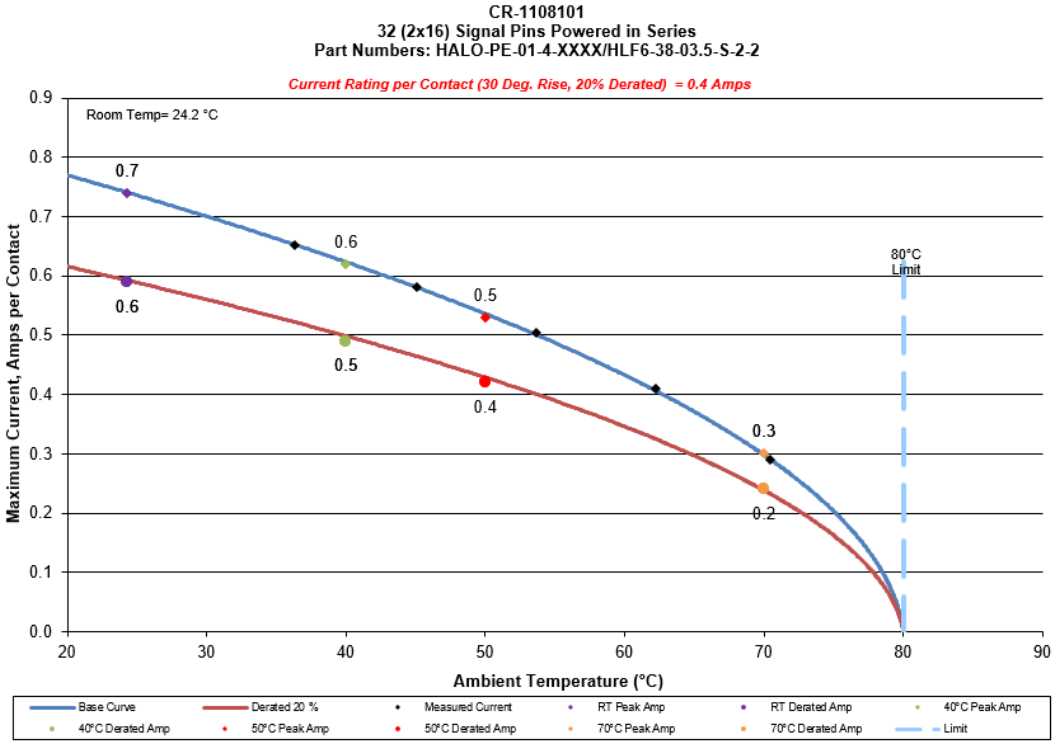
c. Linear configuration with 16 adjacent conductors/contacts powered

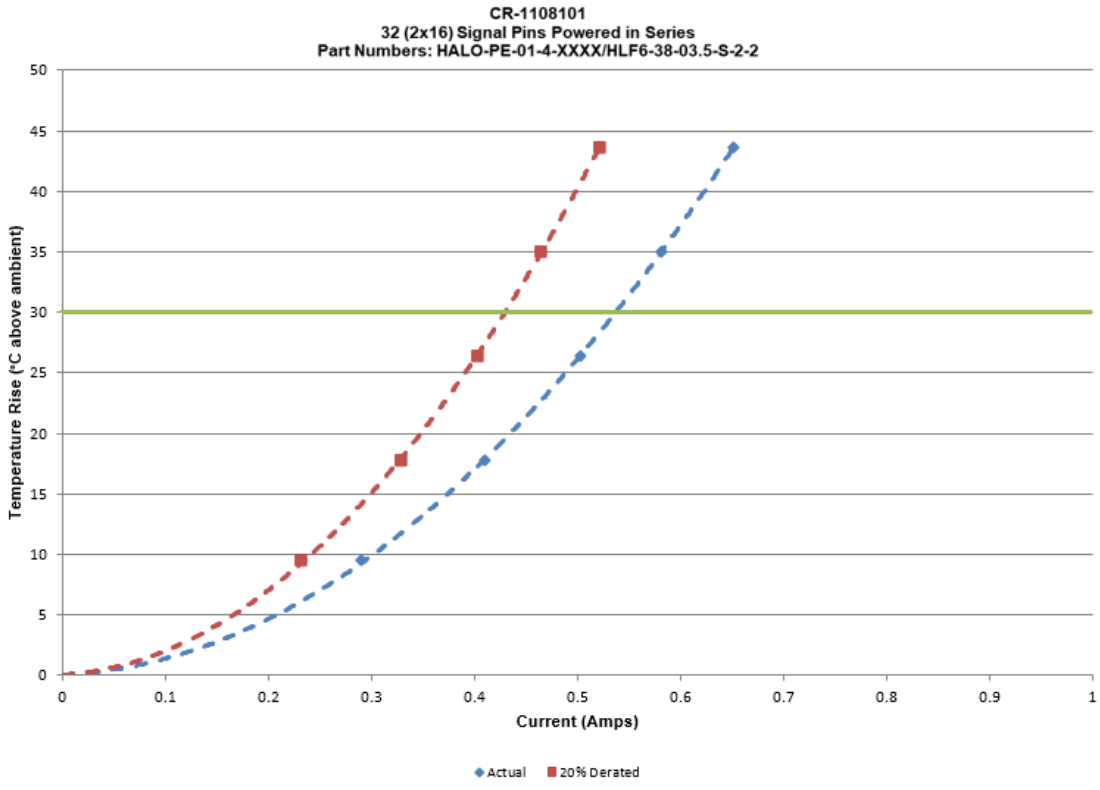




DATA SUMMARIES Continued

d. Linear configuration with 32 adjacent conductors/contacts powered





DATA SUMMARIES Continued

MATING/UNMATING:

Thermal Aging Group

	Initial				After Thermals			
	Mating		**Unmating**		**Mating**		**Unmating**	
	Newtons	Force (Lbs)	Newtons	Force (Lbs)	Newtons	Force (Lbs)	Newtons	Force (Lbs)
Minimum	6.36	1.43	1.91	0.43	4.45	1.00	1.87	0.42
Maximum	7.38	1.66	2.71	0.61	5.03	1.13	4.18	0.94
Average	6.88	**1.55**	2.35	**0.53**	4.69	**1.06**	2.66	**0.60**
St Dev	0.34	0.08	0.24	0.05	0.21	0.05	0.74	0.17
Count	8	8	8	8	8	8	8	8

Mating/Unmating Durability Group

	Initial				After 25 Cycles			
	Mating		**Unmating**		**Mating**		**Unmating**	
	Newtons	Force (Lbs)	Newtons	Force (Lbs)	Newtons	Force (Lbs)	Newtons	Force (Lbs)
Minimum	5.65	1.27	2.00	0.45	6.67	1.50	2.62	0.59
Maximum	7.47	1.68	3.34	0.75	7.96	1.79	4.09	0.92
Average	6.50	**1.46**	2.58	**0.58**	7.25	**1.63**	3.53	**0.79**
St Dev	0.57	0.13	0.42	0.09	0.52	0.12	0.51	0.11
Count	8	8	8	8	8	8	8	8

	After Humidity			
	Mating		**Unmating**	
	Newtons	Force (Lbs)	Newtons	Force (Lbs)
Minimum	5.43	1.22	1.87	0.42
Maximum	7.38	1.66	3.38	0.76
Average	6.32	**1.42**	2.49	**0.56**
St Dev	0.66	0.15	0.50	0.11
Count	8	8	8	8

DATA SUMMARIES Continued

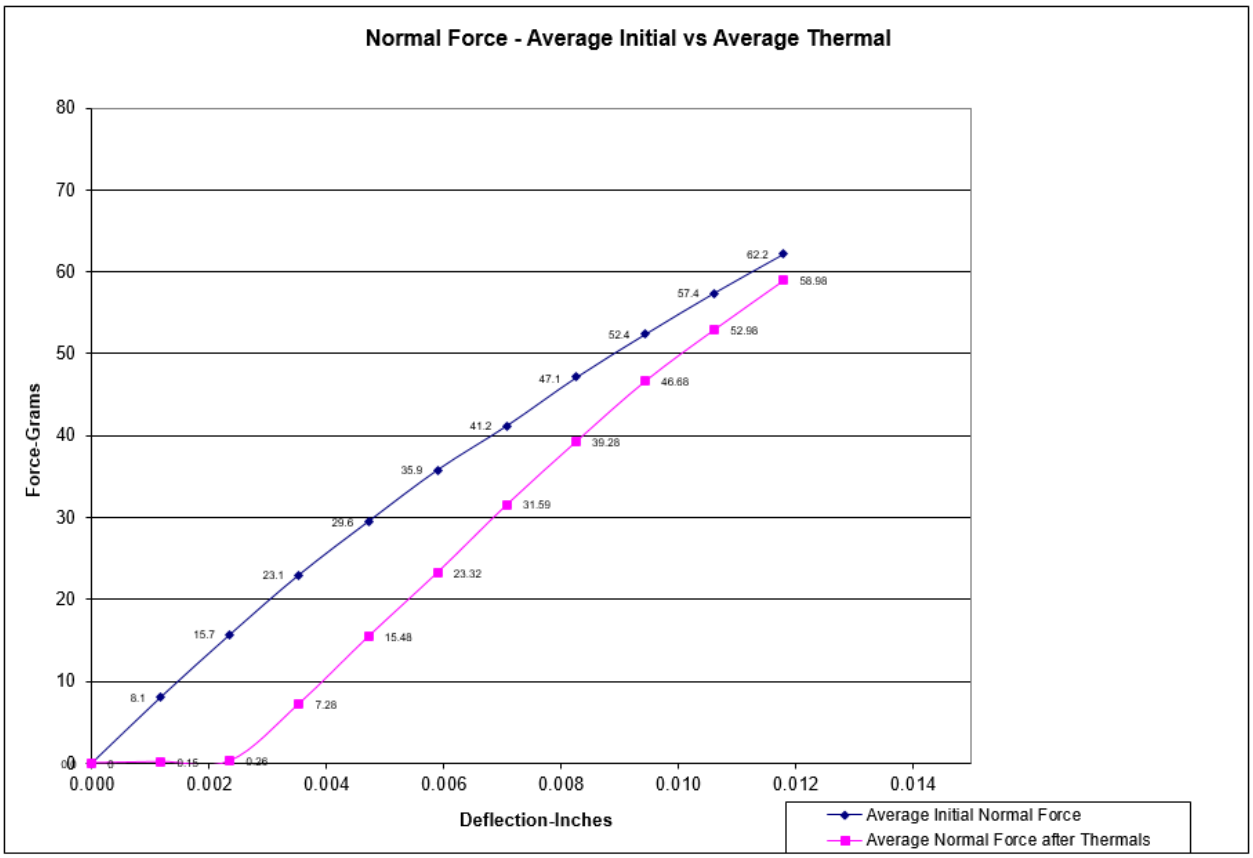
NORMAL FORCE (FOR CONTACTS TESTED OUTSIDE THE HOUSING):

1) Calibrated force gauges are used along with computer-controlled positioning equipment.
2) Typically, 8-10 readings are taken and the averages reported.

Row 1

Initial	Deflections in inches Forces in Grams										
	0.0012	**0.0024**	**0.0035**	**0.0047**	**0.0059**	**0.0071**	**0.0083**	**0.0094**	**0.0106**	**0.0118**	***SET***
Averages	8.08	15.74	23.05	29.55	35.85	41.23	47.10	52.39	57.44	62.19	0.0016
Min	5.90	11.70	18.00	24.70	30.80	34.50	39.20	44.00	47.30	51.40	0.0012
Max	9.80	18.50	27.40	33.90	40.00	45.40	51.80	57.20	63.30	67.00	0.0020
St. Dev	1.308	2.097	2.749	2.782	2.813	3.030	3.444	3.595	4.201	4.125	0.0003
Count	12	12	12	12	12	12	12	12	12	12	12

After Thermals	Deflections in inches Forces in Grams										
	0.0012	**0.0024**	**0.0035**	**0.0047**	**0.0059**	**0.0071**	**0.0083**	**0.0094**	**0.0106**	**0.0118**	***SET***
Averages	0.15	0.26	7.28	15.48	23.32	31.59	39.28	46.68	52.98	58.98	0.0039
Min	0.00	0.00	4.80	13.00	20.50	29.20	36.70	43.80	49.70	55.40	0.0035
Max	0.60	1.30	9.80	17.80	26.20	33.90	41.50	48.70	54.90	60.70	0.0041
St. Dev	0.207	0.390	1.758	1.716	1.933	1.671	1.619	1.390	1.486	1.476	0.0002
Count	12	12	12	12	12	12	12	12	12	12	12

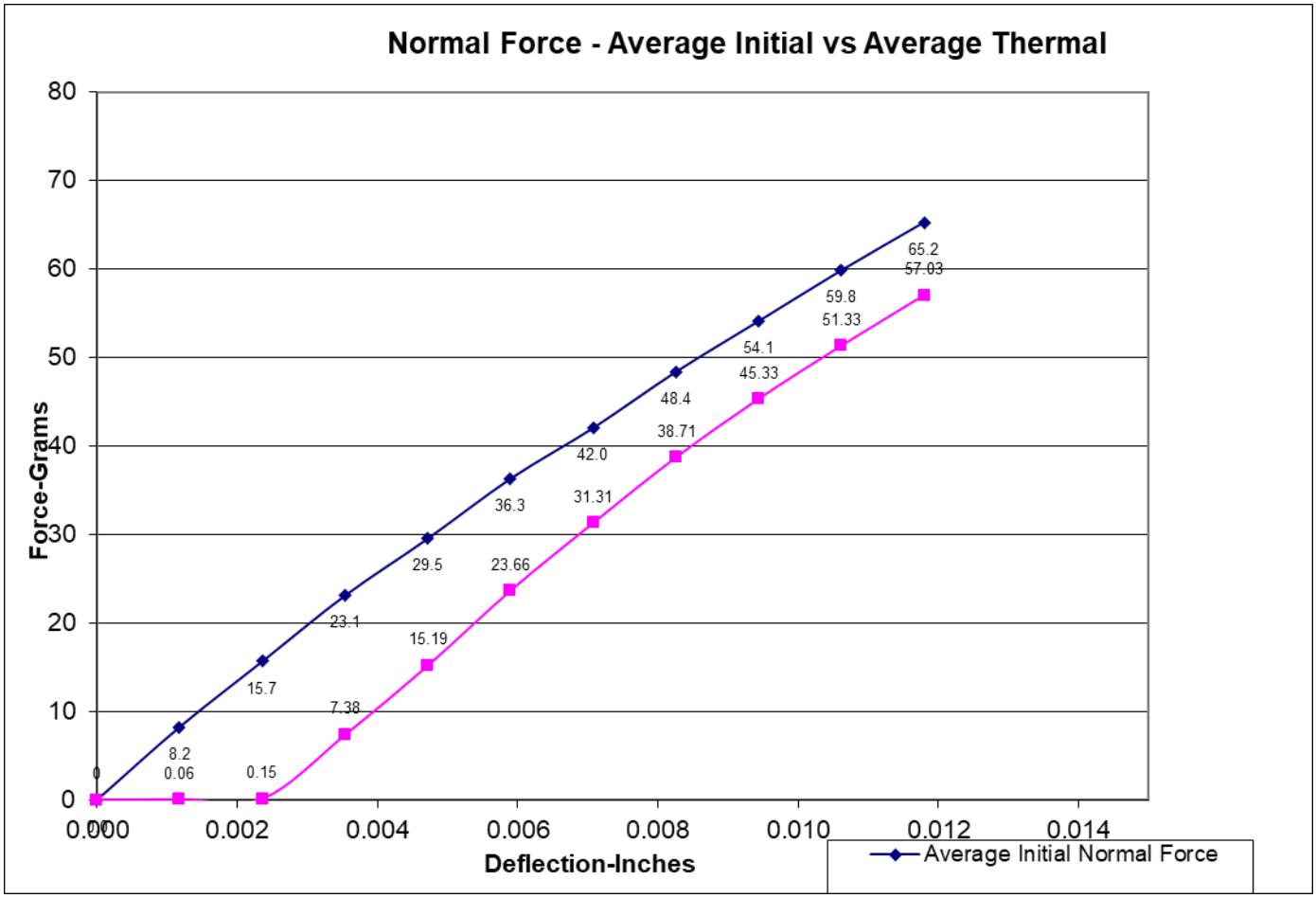


DATA SUMMARIES Continued

Row 2

Initial	Deflections in inches Forces in Grams										
	0.0012	**0.0024**	**0.0035**	**0.0047**	**0.0059**	**0.0071**	**0.0083**	**0.0094**	**0.0106**	**0.0118**	***SET***
Averages	8.24	15.66	23.08	29.52	36.28	42.02	48.35	54.08	59.83	65.24	0.0012
Min	7.00	13.70	18.60	23.00	28.20	34.00	39.60	46.00	50.80	55.70	0.0008
Max	9.50	17.40	25.00	32.50	40.20	46.30	52.70	58.50	64.70	70.10	0.0016
St. Dev	0.746	1.186	1.939	2.495	3.058	3.133	3.397	3.211	3.641	3.818	0.0002
Count	12	12	12	12	12	12	12	12	12	12	12

After Thermals	Deflections in inches Forces in Grams										
	0.0012	**0.0024**	**0.0035**	**0.0047**	**0.0059**	**0.0071**	**0.0083**	**0.0094**	**0.0106**	**0.0118**	***SET***
Averages	0.06	0.15	7.38	15.19	23.66	31.31	38.71	45.33	51.33	57.03	0.0040
Min	0.00	0.00	4.50	11.00	19.00	26.20	33.60	40.00	46.10	52.30	0.0036
Max	0.30	1.20	10.30	18.40	26.80	34.60	42.20	48.80	54.90	60.60	0.0042
St. Dev	0.108	0.345	2.015	2.631	2.493	2.659	2.813	2.743	2.586	2.536	0.0002
Count	12	12	12	12	12	12	12	12	12	12	12



DATA SUMMARIES Continued

INSULATION RESISTANCE (IR):

	Pin to Pin		
	Mated	Unmated	Unmated
Minimum	**HALO/HLF6**	**HALO**	**HLF6**
Initial	45000	45000	45000
Thermal	45000	45000	45000
Humidity	45000	45000	45000

	Row to Row		
	Mated	Unmated	Unmated
Minimum	**HALO/HLF6**	**HALO**	**HLF6**
Initial	45000	45000	45000
Thermal	45000	45000	45000
Humidity	45000	45000	45000

	Pin to Ground		
	Mated	Unmated	Unmated
Minimum	**HALO/HLF6**	**HALO**	**HLF6**
Initial	45000	45000	45000
Thermal	45000	45000	45000
Humidity	3514	4500	45000

DIELECTRIC WITHSTANDING VOLTAGE (DWV):

Voltage Rating Summary	
Minimum	**HALO/HLF6**
Break Down Voltage	715
Test Voltage	540
Working Voltage	180

Row to Row	
Initial Test Voltage	Passed
After Thermal Test Voltage	Passed
After Humidity Test Voltage	Passed

Pin to Pin	
Initial Test Voltage	Passed
After Thermal Test Voltage	Passed
After Humidity Test Voltage	Passed

Pin to Ground	
Initial Test Voltage	Passed
After Thermal Test Voltage	Passed
After Humidity Test Voltage	Passed

DATA SUMMARIES Continued

Cable Pull Force:

0° Pull

	Force (lbs)
Minimum	**25.15**
Maximum	30.05
Average	26.89

90° Pull

	Force (lbs)
Minimum	**3.27**
Maximum	4.54
Average	4.03

Cable Flex:

Insulation Resistance minimums, IR

Pin to Pin	
Mated	
Minimum	
Initial	45000
After 200 Flex Cycles	45000

Row to Row	
Mated	
Minimum	
Initial	45000
After 200 Flex Cycles	45000

Pin to Ground	
Mated	
Minimum	
Initial	45000
After 200 Flex Cycles	45000

Dielectric Withstanding Voltage minimums, DWV

Voltage Rating Summary	
Minimum	**HALO/HLF6**
Test Voltage	540

Pin to Pin	
Initial Test Voltage	Passed
After 200 Flex Cycles Test Voltage	Passed

Row to Row	
Initial Test Voltage	Passed
After 200 Flex Cycles Test Voltage	Passed

Pin to Ground	
Initial Test Voltage	Passed
After 200 Flex Cycles Test Voltage	Passed

DATA SUMMARIES Continued

LLCR Durability:

1) A total of 192 points were measured.
2) EIA-364-23, *Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets.*
3) A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
4) The following guidelines are used to categorize the changes in LLCR as a result from stressing.
   a. <= +5.0 mOhms: ---------- Stable
   b. +5.1 to +10.0 mOhms: ---------- Minor
   c. +10.1 to +15.0 mOhms: ---------- Acceptable
   d. +15.1 to +50.0 mOhms: ---------- Marginal
   e. +50.1 to +1000 mOhms ---------- Unstable
   f. >+1000 mOhms: ---------- Open Failure

	LLCR Measurement Summaries by Pin Type			
Date	12/18/2024	12/19/2024	12/31/2024	1/10/2025
Room Temp (Deg C)	23	23	23	23
Rel Humidity (%)	51	51	51	51
Technician	Peter Chen	Peter Chen	Peter Chen	Peter Chen
mOhm values	Actual **Initial**	**Delta Cycles**	**Delta Therm Shck**	**Delta Humidity**
	Pin Type: Signal 1			
Average	359.24	5.48	5.58	5.43
St. Dev.	30.06	4.06	4.31	3.94
Min	299.2	0.03	0.05	0.07
Max	423.16	14.69	14.92	14.89
Summary Count	192	192	192	192
Total Count	192	192	192	192

LLCR Delta Count by Category						
	Stable	**Minor**	**Acceptable**	**Marginal**	**Unstable**	**Open**
mOhms	**<=5**	**>5 & <=10**	**>10 & <=15**	**>15 & <=50**	**>50 & <=1000**	**>1000**
Cycles	**107**	**47**	**38**	**0**	**0**	**0**
Therm Shck	**111**	**43**	**38**	**0**	**0**	**0**
Humidity	**97**	**66**	**29**	**0**	**0**	**0**

DATA SUMMARIES Continued

LLCR Thermal Aging:

1) A total of 192 points were measured.
2) EIA-364-23, *Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets.*
3) A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
4) The following guidelines are used to categorize the changes in LLCR as a result from stressing.
   a. <= +5.0 mOhms: ---------- Stable
   b. +5.1 to +10.0 mOhms:---------- Minor
   c. +10.1 to +15.0 mOhms: ---------- Acceptable
   d. +15.1 to +50.0 mOhms: ---------- Marginal
   e. +50.1 to +1000 mOhms: ---------- Unstable
   f. >+1000 mOhms:---------- Open Failure

	LLCR Measurement Summaries by Pin Type			
Date	12/19/2024	12/31/2024		
Room Temp (Deg C)	23	23		
Rel Humidity (%)	54	51		
Technician	Peter Chen	Peter Chen		
mOhm values	Actual **Initial**	**Delta** **Thermal**		
	Pin Type: Signal 1			
Average	351.05	6.28		
St. Dev.	30.66	4.25		
Min	281.77	0.24		
Max	424.39	14.98		
Summary Count	192	192		
Total Count	192	192		

LLCR Delta Count by Category						
	Stable	**Minor**	**Acceptable**	**Marginal**	**Unstable**	**Open**
mOhms	**<=5**	**>5 & <=10**	**>10 & <=15**	**>15 & <=50**	**>50 & <=1000**	**>1000**
Thermal	**93**	**57**	**42**	**0**	**0**	**0**

DATA SUMMARIES Continued

LLCR Gas Tight:

1) A total of 192 points were measured.
2) EIA-364-23, *Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets.*
3) A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
4) The following guidelines are used to categorize the changes in LLCR as a result from stressing.
   a. <= +5.0 mOhms: ---------- Stable
   b. +5.1 to +10.0 mOhms: ---------- Minor
   c. +10.1 to +15.0 mOhms: ---------- Acceptable
   d. +15.1 to +50.0 mOhms: ---------- Marginal
   e. +50.1 to +1000 mOhms: ---------- Unstable
   f. >+1000 mOhms: ---------- Open Failure

	LLCR Measurement Summaries by Pin Type			
Date	12/24/2024	12/26/2024		
Room Temp (Deg C)	23	23		
Rel Humidity (%)	51	51		
Technician	Peter Chen	Peter Chen		
mOhm values	Actual	**Delta**		
	Initial	**Acid Vapor**		
	Pin Type: Signal 1			
Average	353.14	3.33		
St. Dev.	30.85	3.39		
Min	283.85	0		
Max	424.38	14.6		
Summary Count	192	192		
Total Count	192	192		

LLCR Delta Count by Category						
	Stable	**Minor**	**Acceptable**	**Marginal**	**Unstable**	**Open**
mOhms	**<=5**	**>5 & <=10**	**>10 & <=15**	**>15 & <=50**	**>50 & <=1000**	**>1000**
Acid Vapor	**152**	**27**	**13**	**0**	**0**	**0**

DATA SUMMARIES Continued

LLCR Shock &Vibration:

1). A total of 256 points were measured.
2). EIA-364-23, *Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets.*
3). The following guidelines are used to categorize the changes in LLCR as a result from stressing.
   a. <= +5.0 mOhms: ---------- Stable
   b. +5.1 to +10.0 mOhms: ---------- Minor
   c. +10.1 to +15.0 mOhms: ---------- Acceptable
   d. +15.1 to +50.0 mOhms: ---------- Marginal
   e. +50.1 to +1000 mOhms ---------- Unstable
   f. >+1000 mOhms: ---------- Open Failure

	LLCR Measurement Summaries by Pin Type			
Date	6/30/2025	7/4/2025		
Room Temp (Deg C)	23	23		
Rel Humidity (%)	51	51		
Technician	Peter Chen	Peter Chen		
mOhm values	Actual	**Delta**		
	Initial	**Shock-Vib**		
	Pin Type: Signal 1			
Average	362.4	3.0		
St. Dev.	27.8	2.7		
Min	301.5	0.0		
Max	430.9	14.3		
Summary Count	256	256		
Total Count	256	256		

LLCR Delta Count by Category						
	Stable	**Minor**	**Acceptable**	**Marginal**	**Unstable**	**Open**
mOhms	**<=5**	**>5 & <=10**	**>10 & <=15**	**>15 & <=50**	**>50 & <=1000**	**>1000**
Shock-Vib	213	35	8	0	0	0

Nanosecond Event Detection:

Shock and Vibration Event Detection Summary	
Contacts tested	60
Test Condition	C, 50g's, 11ms, Half-Sine
Shock Events	0
Test Condition	V-B, 7.56 rms g
Vibration Events	0
Total Events	0

EQUIPMENT AND CALIBRATION SCHEDULES

Equipment #: HZ-TCT-01
Description: Normal force analyzer
Manufacturer: Mecmesin Multitester
Model: Mecmesin Multitester 2.5-i
Serial #: 08-1049-04
Accuracy: Last Cal: 4/26/2025, Next Cal: 4/25/2026

Equipment #: HZ-OV-01
Description: Oven
Manufacturer: Huida
Model: CS101-1E
Serial #: CS101-1E-B
Accuracy: Last Cal: 12/13/2024, Next Cal: 12/12/2025

Equipment #: HZ-THC-01
Description: Humidity transmitter
Manufacturer: Thermtron
Model: SM-8-8200
Serial #: 38846
Accuracy: Last Cal: 2/28/2025, Next Cal: 2/27/2026

Equipment #: HZ-TSC-01
Description: Vertical Thermal Shock Chamber
Manufacturer: Cincinnatti Sub Zero
Model: VTS-3-6-6-SC/AC
Serial #: 10-VT14994
Accuracy: See Manual
… Last Cal: 06/28/2025, Next Cal: 06/27/2026

Equipment #: HZ-HPM-01
Description: NA9636H
Manufacturer: Ainuo
Model: 6031A
Serial #: 089601091
Accuracy: Last Cal: 3/7/2025, Next Cal: 3/6/2026

Equipment #: HZ-MO-05
Description: Micro-ohmmeter
Manufacturer: Keithley
Model: 3706
Serial #: 1285188
Accuracy: Last Cal: 11/15/2024, Next Cal: 11/14/2025

EQUIPMENT AND CALIBRATION SCHEDULES Continued

Equipment #: SVC-01
Description: Shock & Vibration Table
Manufacturer: Data Physics
Model: LE-DSA-10-20K
Serial #: 10037
Accuracy: See Manual
… Last Cal: 11/31/2024, Next Cal: 11/31/2025

Equipment #: ACLM-01
Description: Accelerometer
Manufacturer: PCB Piezotronics
Model: 352C03
Serial #: 115819
Accuracy: See Manual
… Last Cal: 07/09/2025, Next Cal: 07/09/2026

Equipment #: ED-03
Description: Event Detector
Manufacturer: Analysis Tech
Model: 32EHD
Serial #: 1100604
Accuracy: See Manual
… Last Cal: 06/04/2025, Next Cal: 06/04/2026